IEC 60512-16-18

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INTERNATIONAL STANDARD

NORME INTERNATIONALE

Connectors for electronic equipment – Tests and measurements – Part 16-18: Mechanical tests on contacts and terminations – Test 16r: Deflection of contacts, simulation

Connecteurs pour équipements électroniques – Essais et mesures – Partie 16-18: Essais mécaniques des contacts et des sorties – Essai 16r: Débattement des contacts, simulation

IEC 60512-16-18:2008

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CONNECTORS FOR ELECTRONIC EQUIPMENT – TESTS AND MEASUREMENTS –

Part 16-18: Mechanical tests on contacts and terminations – Test 16r: Deflection of contacts, simulation

FOREWORD

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International Standard IEC 60512-16-18 has been prepared by subcommittee 48B: Connectors, of IEC technical committee 48: Electromechanical components and mechanical structures for electronic equipment.

This standard cancels and replaces test 16r of IEC 60512-8, issued in 1993. This standard is to be read in conjunction with IEC 60512-1 and IEC 60512-1-100 which explains the structure of the IEC 60512 series.

The text of this standard is based on the following documents:

FDIS	Report on voting
48B/1875/FDIS	48B/1907/RVD

Full information on the voting for the approval of this standard can be found in the report on voting indicated in the above table.

This publication has been drafted in accordance with the ISO/IEC Directives, Part 2.

A list of all parts of the IEC 60512 series, under the general title *Connectors for electronic equipment – Tests and measurements*, can be found on the IEC website.

The committee has decided that the contents of this publication will remain unchanged until the maintenance result date indicated on the IEC web site under "http://webstore.iec.ch" in the data related to the specific publication. At this date, the publication will be

- reconfirmed;
- withdrawn;
- replaced by a revised edition; or
- amended.

CONNECTORS FOR ELECTRONIC EQUIPMENT – TESTS AND MEASUREMENTS –

Part 16-18: Mechanical tests on contacts and terminations – Test 16r: Deflection of contacts, simulation

1 Scope and object

This part of IEC 60512, when required by the detail specification, is used for testing electomechanical components within the scope of technical committee 48. It may also be used for similar devices when specified in a detail specification.

The object of this part of IEC 60512 is to detail a standard test method to measure the deflection of a simulated contact in its cavity or housing.

Although this test method is intended for cylindrical male contacts, and is particularly applicable to those where the contacts fit into an insert, which may have some elasticity, its use for contacts with other geometries and housing details, is not excluded. In which case, the detail specification should contain sufficient detail, given under Clause 5, to enable the test to be done.

2 Normative references

The following referenced documents are indispensable for the application of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

IEC 60512-1-1*, Connectors for electronic equipment – Tests and measurements – Part 1-1: General examination – Test 1a: Visual examination*

3 Preparations

3.1 Preparation of specimen

The specimen shall consist of a housing, with an insert or other contact-receiving connector body or device. Any preconditioning given in the component detail specification shall be applied. Five such specimens shall be prepared.

3.2 Equipment

A test pin (gauge pin) shall be provided, the design of which shall replicate those parts of the contact normally fitted into the cavity that have relevance to this test.

A universal testing machine suitable for the test procedure detailed in Clause 4 shall be required, equipped with all relevant test fixtures needed to hold the specimen under test.

3.3 Mounting

If mounting of the specimen is appropriate, it shall be as specified in the component detail specification.

The specimen shall not be mated to its corresponding, or other, component.